

ABSTRACT OF THE DISCLOSURE

The number of failure bits is counted with respect to each row and each column in a fail bit map (9), to find respective average numbers of failure bits with respect to rows and columns. One-half of the average number of failure bits of rows is defined as a threshold value of rows, and one-half of the average number of failure bits of columns is defined as a threshold value of columns. Thereafter, on the basis of the respective threshold values of rows and columns, the number of failure bits is converted to digital form with respect to each row and each column. The respective average values of the digitized numbers of failure bits with respect to rows and columns are calculated, which are respectively referred to as average values of rows and columns. It is determined that a semiconductor device contains a block failure in a row direction, a block failure in a column direction, or a random block failure.